

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
289272US2PCTSERIAL NO.  
10/574,702

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Helene JOISTEN, et al.

FILING DATE

April 5, 2006

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/JMP/	AA	2 743 416	04/24/56	KELLY, Joseph M. Jr.			
/JMP/	AB	6 060 181	5/9/2000	STOLK, Richard D.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/JMP/	<del>AO</del>	1 371 453	9/4/1964	FR		NO
	<del>AP</del>	942 468	2/9/1949	FR		NO
	<del>AQ</del>	1 597 324	9/3/1981	GB		NO
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

/JMP/	<del>AW</del>	KAWAHITO, Shoji et al., "High-Resolution Micro-Fluxgate Sensing Elements Using Closely Coupled Coil Structures", Sensors and Actuators A, Vol. 54, No. 1-3, Pages 612-617, 1996.		
	<del>AX</del>	RUSTENBACH, J. et al., "Fluxgate Magnetometers for Balloons and Small Satellites", Elsevier Science, Vol. 35, Pages 89-98, 1995.		
	<del>AY</del>	GOTTFRIED-GOTTFRIED, R. et al., "A Miniaturized Magnetic-Field Sensor System Consisting of a Planar Fluxgate Sensors and a CMOS Readout Circuitry", Sensor and Actuators A, Vol. 54, Pages 443-447, 1996.		
	<del>AZ</del>	LASSAHN, Martin et al., "A Multi-Channel Magnetometer for Field Structure Measurement Based on Time Encoded Flux-Gate Sensors, IEEE Transactions on Instrumentation and Measurement, Vol. 42, No. 2, April 1993.		<input type="checkbox"/> Additional References sheet(s) attached

Examiner /Jay M. Patidar/

Date Considered 08/30/2007

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.